

Notice of References CitedApplication No.
09/207,546

Applicant(s)

DeGendt et al

Examiner

Shamim AhmedGroup Art Unit
1746

Page 1 of 1

U.S. PATENT DOCUMENTS

*		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
	A	5,560,857	10/1996	Sakon et al	510	175
	B	6,080,531	6/2000	Carter et al.	430	329
	C					
	D					
	E					
	F					
	G					
	H					
	I					
	J					
	K					
	L					
	M					

FOREIGN PATENT DOCUMENTS

*		DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS
	N						
	O						
	P						
	Q						
	R						
	S						
	T						

NON-PATENT DOCUMENTS

*		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
	U	Ohmi et al., "Native Oxide Groth and Organic Impurity Removal on Si Surface with Ozone-Injected Ultrapure Water." Journal of Electrochemical Society, vol.140, No.3, pp.804-810.	3/1993
x	V	K.Sehested et al., "Decomposition of Ozone in Aqueous Acetic Acid Solution (pH 0-4)" J. Phys. Chem, 96, pp. 1005-1009.	1992
x	W	Heyns et al., "New wet cleaning strategies for obtaining highly reliable thin oxide." MRP Symposium Proceeding on Material research Society,	4/1993
	X	Werner Kern, "Handbook of Semiconductor Water Cleaning Technology" pages 49-52.	1993

* A copy of this reference is not being furnished with this Office action.
(See Manual of Patent Examining Procedure, Section 707.05(a).)